## Notice of References Cited Application/Control No. 10/618,473 Examiner VanThu Nguyen Applicant(s)/Patent Under Reexamination DENG ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0252573 A1	12-2004	Hanson et al.	365/229
	В	US-			
	С	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
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## **FOREIGN PATENT DOCUMENTS**

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## **NON-PATENT DOCUMENTS**

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